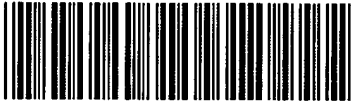


Search Notes

Application No.

09/672,738

Examiner

Fritz Alphonse

Applicant(s)

TANAKA, YUKIO

Art Unit

2133

SEARCHED

Class	Subclass	Date	Examiner
34	92	11/24/2004	FA
	87		
	99		
	100		
	103		
	204		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
345	92	11/26/2004	FA
	99, 100		
	204		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
345/\$.ccls. display with TFT same matrix (source and gate) near5 driver select\$4 near4 signal same second near4 gate	11/26/2004	FA
(pixel oe picture) near5 (portion or section or element) same (source and gate) near4 driver same substrate		
select\$4 near4 signal same static select\$4 near4 signal same static near4 state		